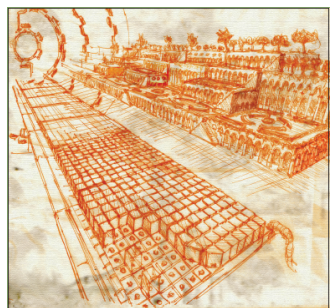




CMS Tracker Week
Phase I Upgrade Plenary
15 May 2013



Update on Test Beam Results with Irradiated PSI46dig

Matteo Centis Vignali, Ganna Dolinska, Erika Garutti,
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Chips Under Test

Four psi46dig Read Out Chips (ROCs) irradiated

Two chips irradiated @ CERN PS - 24 GeV protons

- ♦ psi46dig chip 202 with sensor

D = 3 MRad

$\mathcal{F} = 0.91 \cdot 10^{14} / \text{cm}^2 (\pm 7.4\%) *$

- ♦ psi46dig chip 203 with sensor

D = 13 MRad

$\mathcal{F} = 3.77 \cdot 10^{14} / \text{cm}^2 (\pm 7.6\%) *$

Two chips irradiated @ Karlsruhe p Zyklotron

- ♦ psi46dig chip 204 without sensor

D = 37.5 MRad

- ♦ psi46digtrig chip 214 without sensor

D = 113 MRad

* <https://irradiation.web.cern.ch/irradiation/Dosimeter/Sets-2012.htm>



Tracker Radiation Dose

[CMS-TDR-011]

Layer 1: 1 MGy

Layer 2: 400 kGy

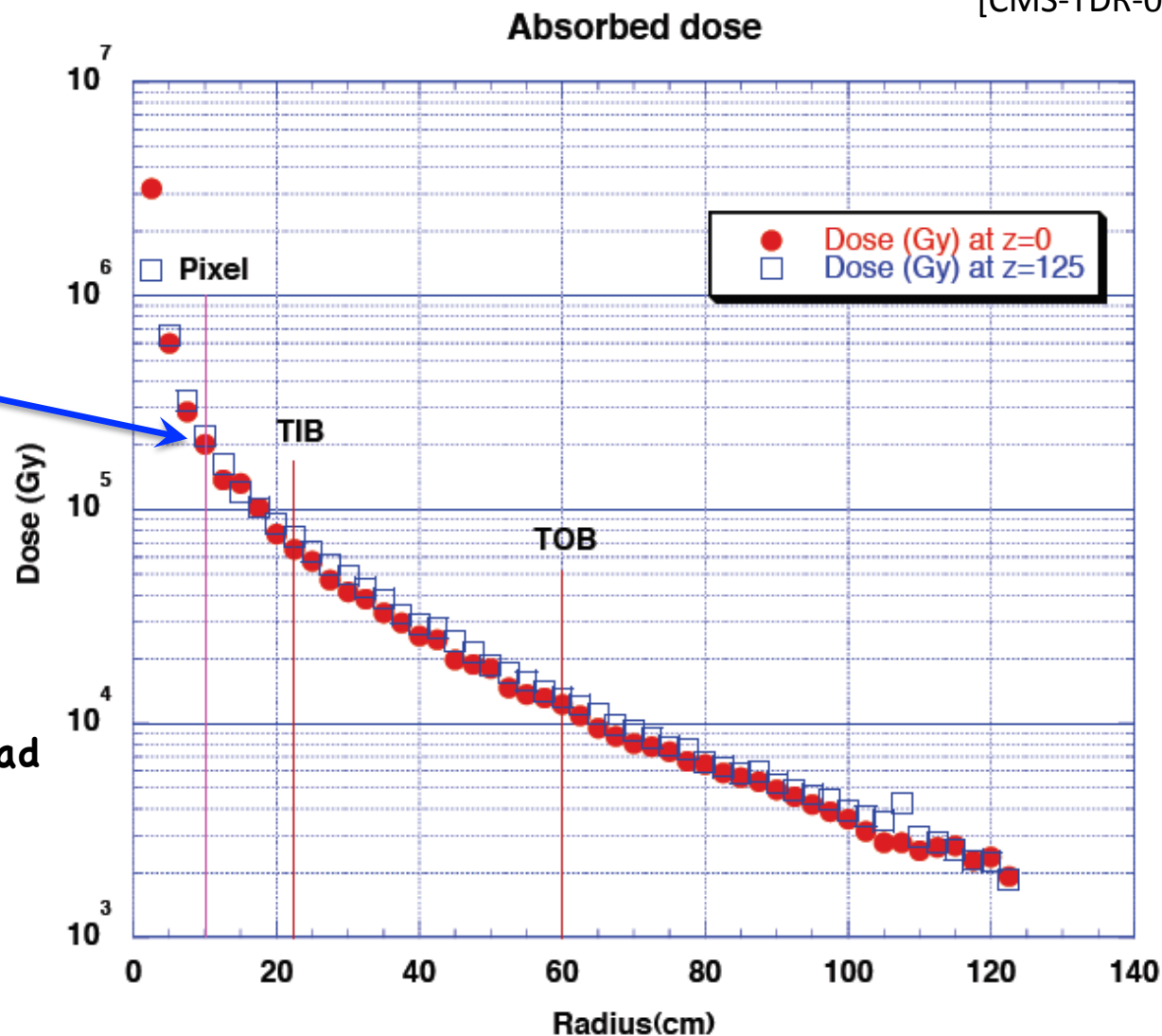
Layer 3: 200 kGy

Layer 4: 150 kGy

100 kGy = 10 MRad

Fluence:

$3 \cdot 10^{13}/\text{cm}^2$ mips $\sim$ 1MRad



Test Beam Results

**Common
scintillator
trigger**

CMS REF

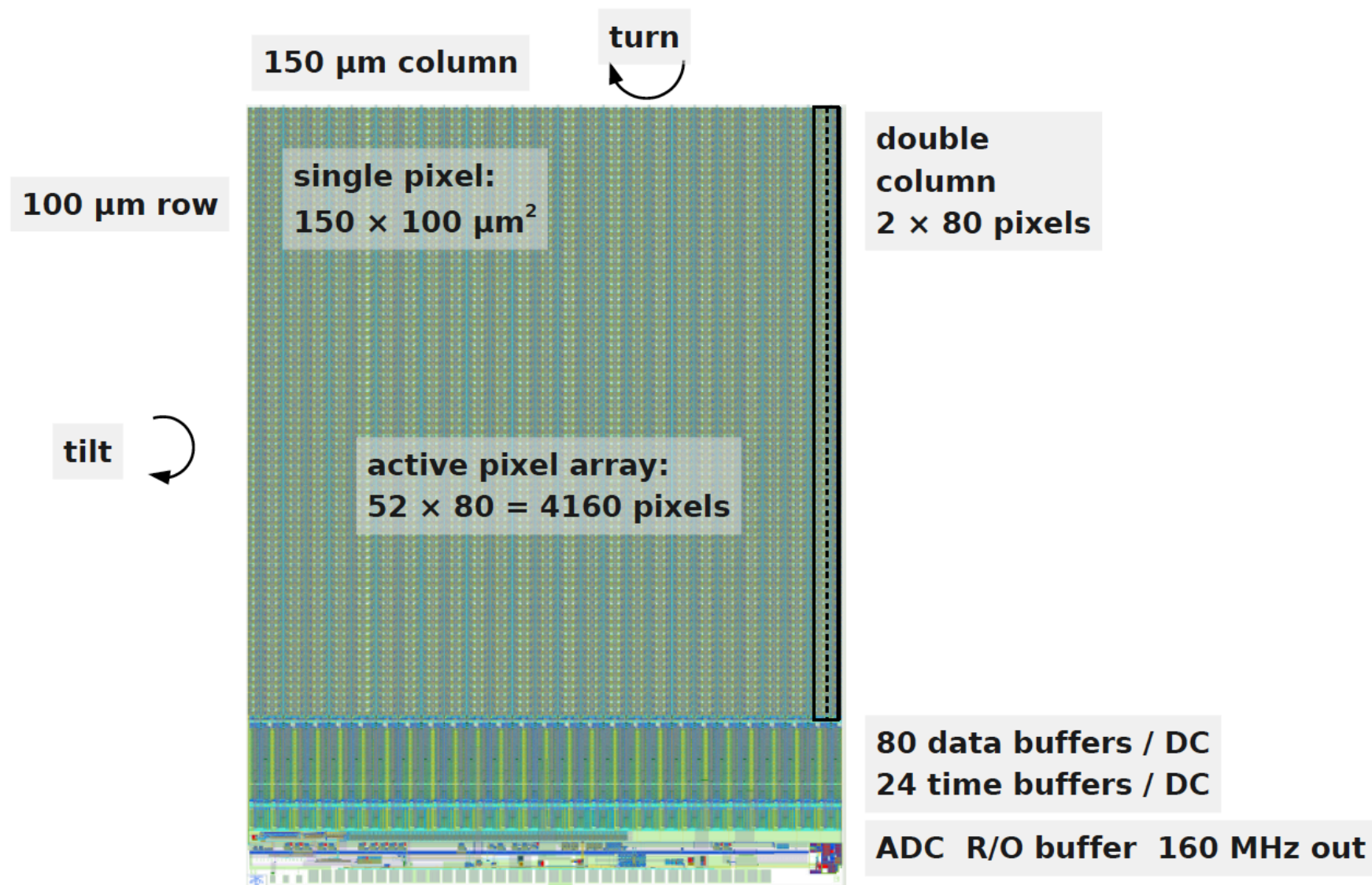
**Mimosa Telescope
3 planes downstream**

CMS pixel

**Mimosa Telescope
3 planes upstream
3.3 μm resolution**

**4.4 GeV positrons
500 Hz/cms²**

psi46dig Pixel Read Out Chip

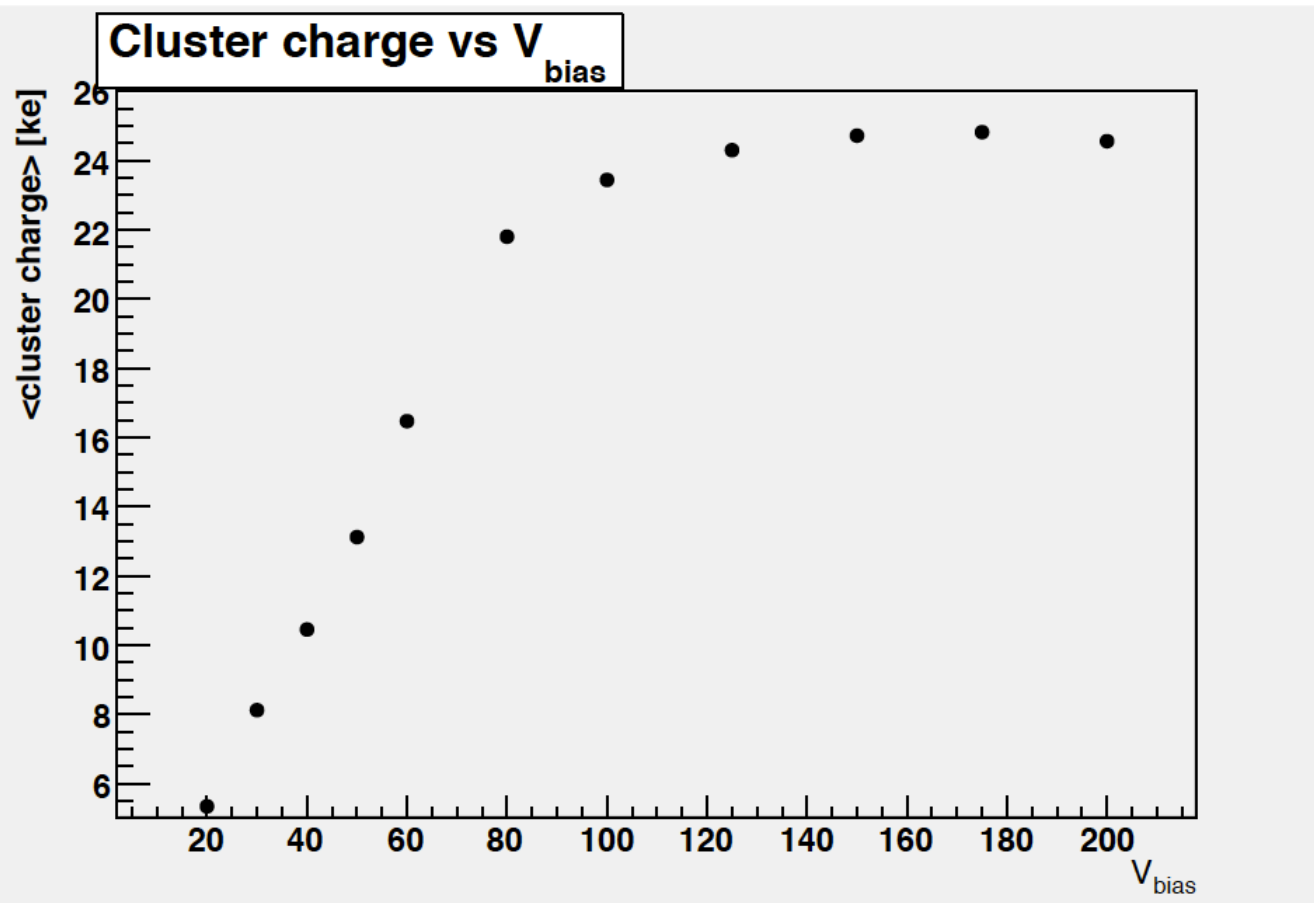


Test Beam Program

Beam Energy set to 4.4 GeV (e^-)

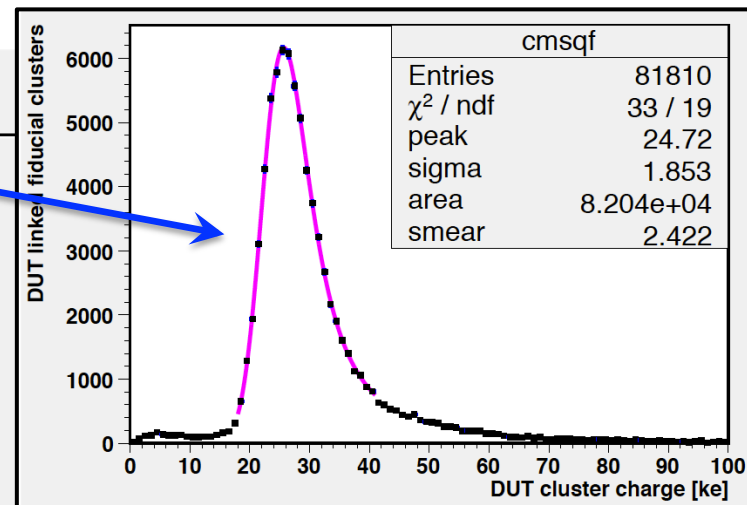
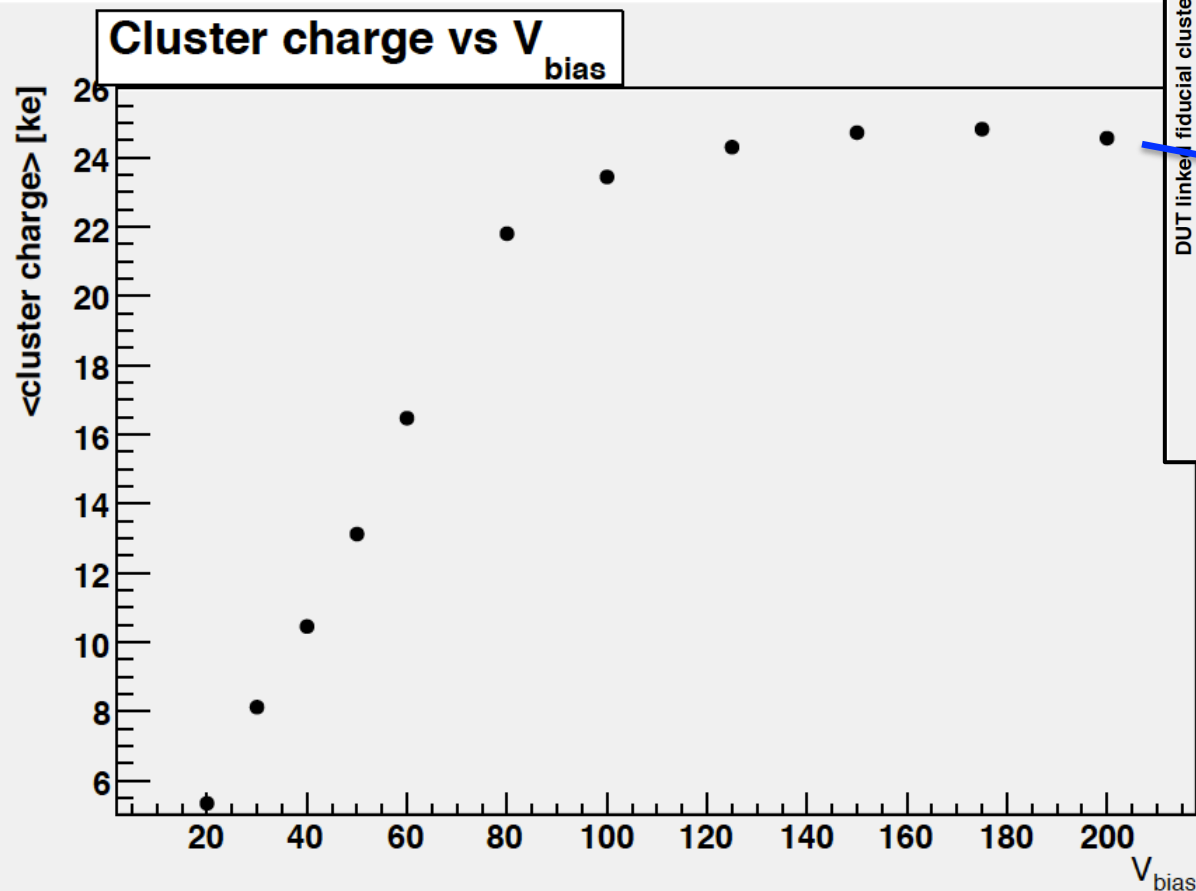
- ♦ psi46dig chip 202
 - > no cooling
 - > tilt 19, later add turn 28
 - > bias voltage scan at low threshold
 - > threshold scan at high bias voltage
- ♦ psi46dig chip 203
 - > cooling with chiller at -15°C (expected -5°C at the sensor)
 - > bias voltage scan and threshold with tilt and turn
 - > bias voltage and tilt scan at low threshold, no turn

Cluster Charge - Chip 202



- ♦ psi46dig chip 202
 - > $D = 3$ Mrad
 - > $I_A = 25$ mA
 - > threshold = 35
 - > tilt = 19.2°
 - > no turn
- ♦ Full depletion around -100 V

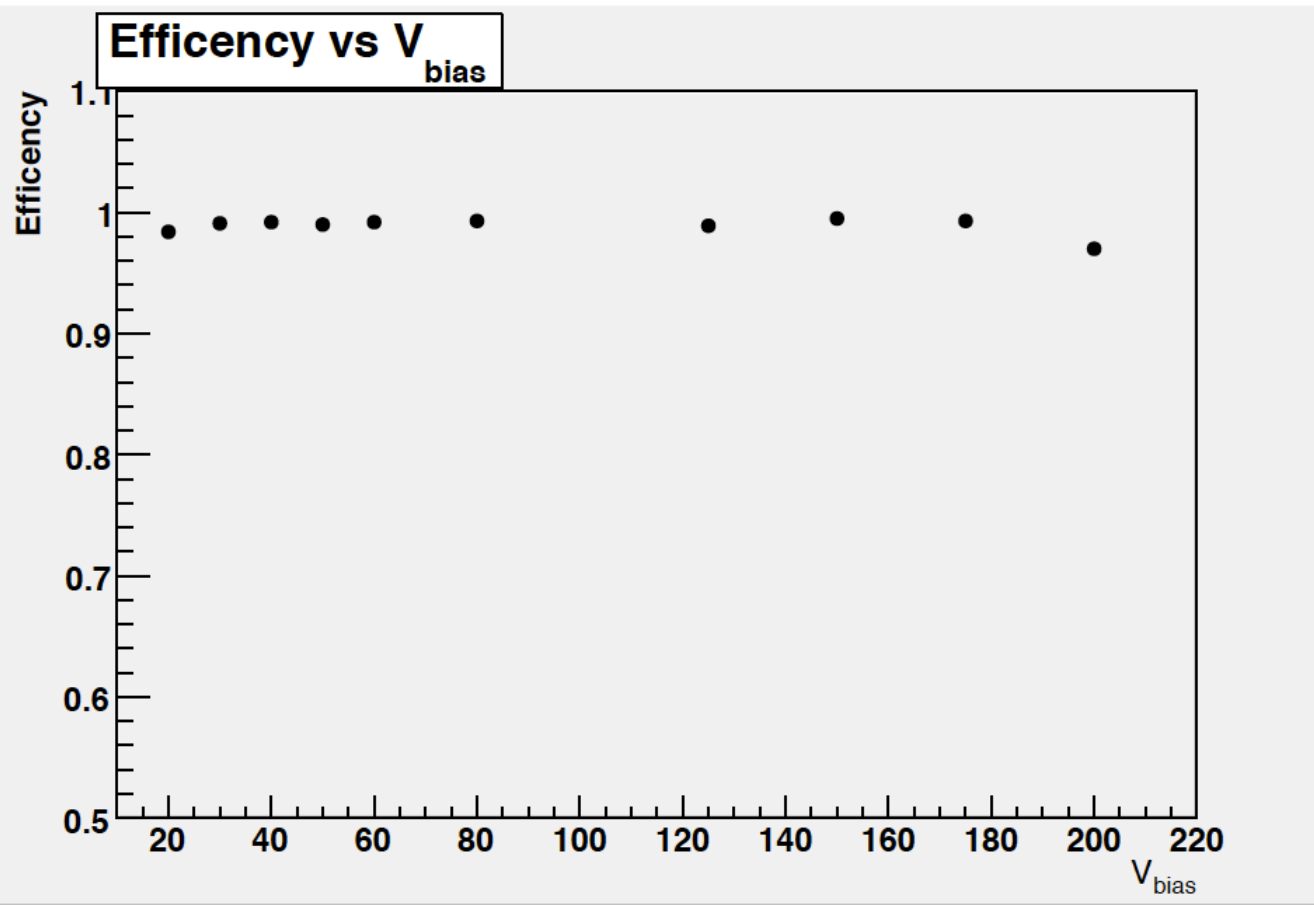
Cluster Charge - Chip 202



◆ Cluster charge distribution fit by Landau $\otimes$ Gauss

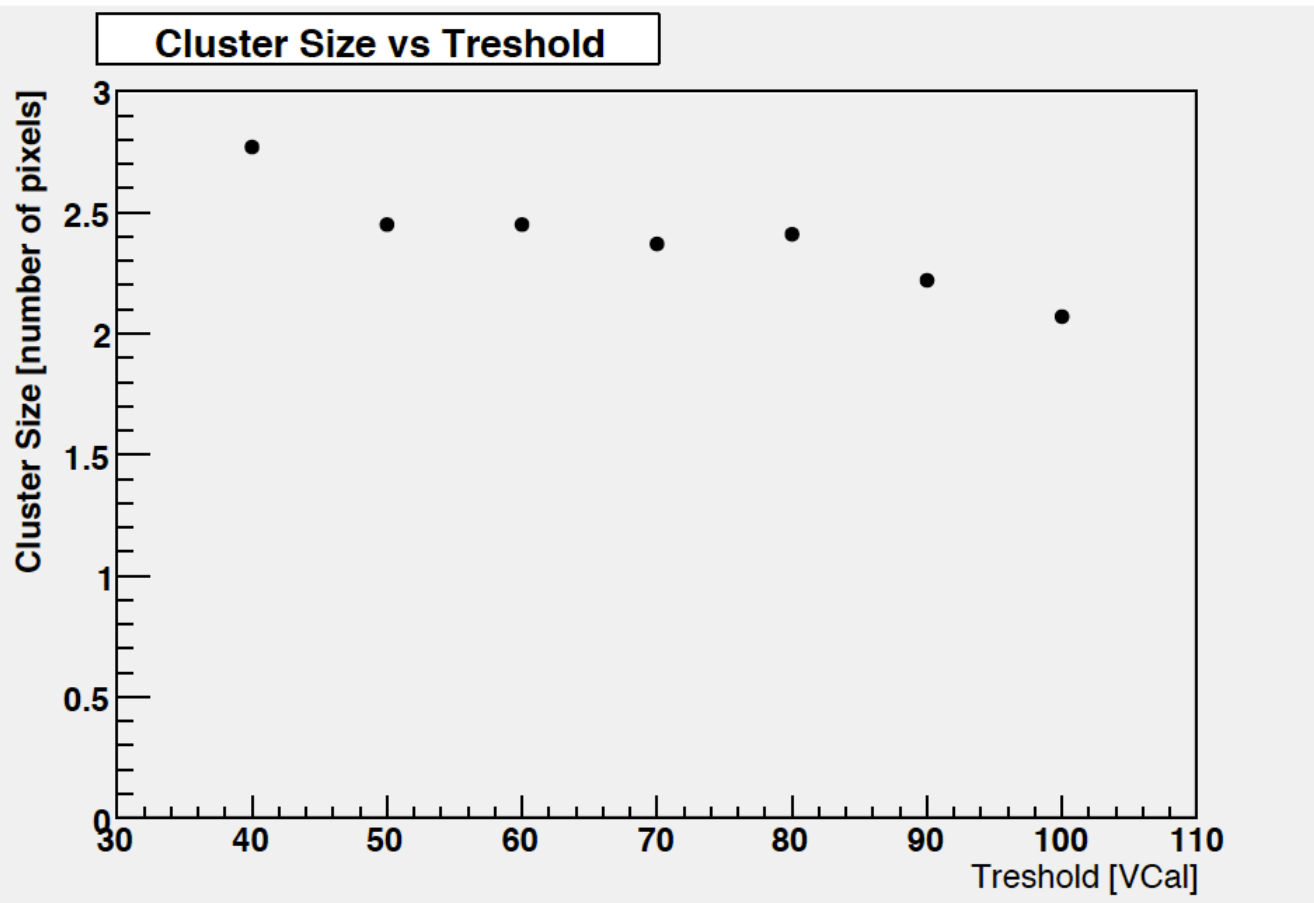
Gain calibration:
Weibull fit,
assume 50e/DAC

Efficiency - Chip 202



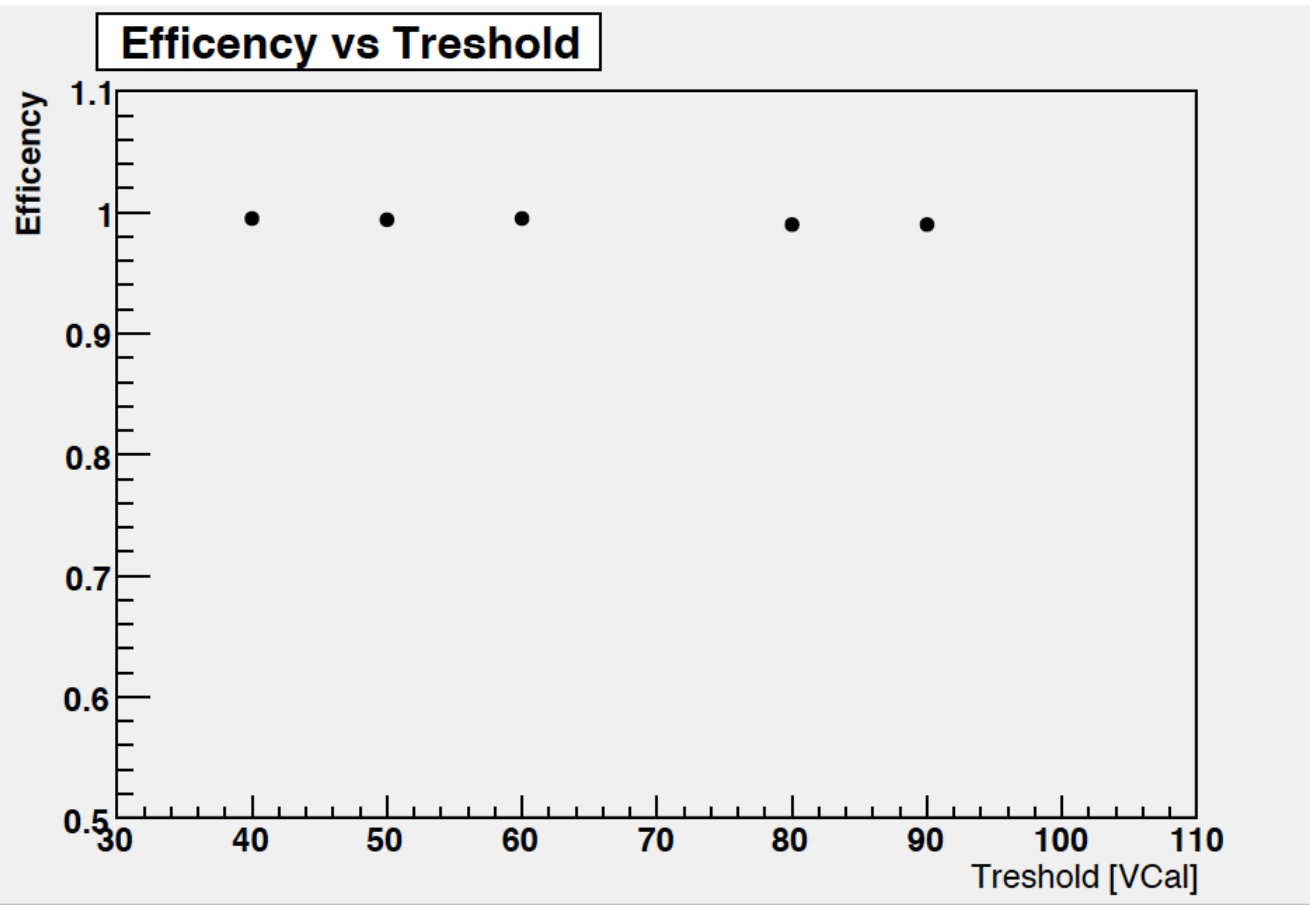
- ♦ psi46dig chip 202
 - > $D = 3$ Mrad
 - > $I_A = 25$ mA
 - > threshold = 35
 - > tilt = 19.2°
 - > no turn

Cluster Size - Chip 202



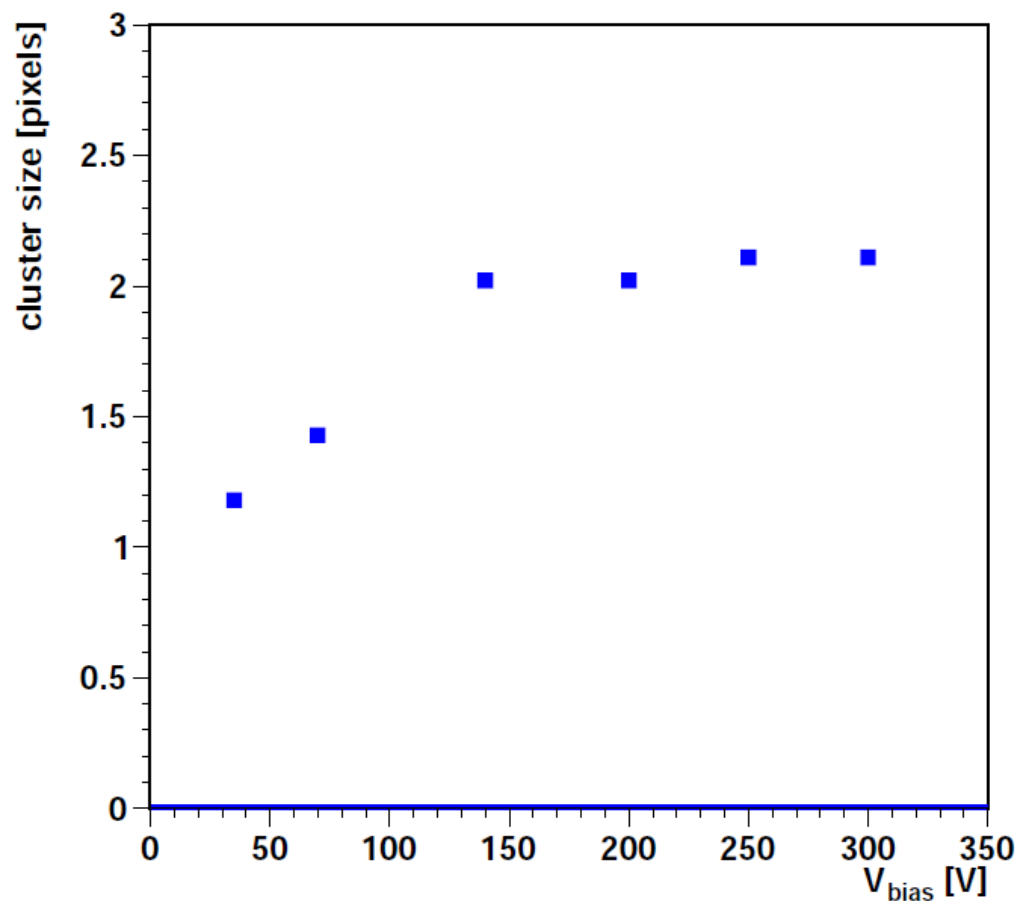
- ♦ psi46dig chip 202
 - > $D = 3$ Mrad
 - > $I_A = 25$ mA
 - > threshold = 35
 - > tilt = 20.3°
 - > turn = 28.5°

Efficiency - Chip 202



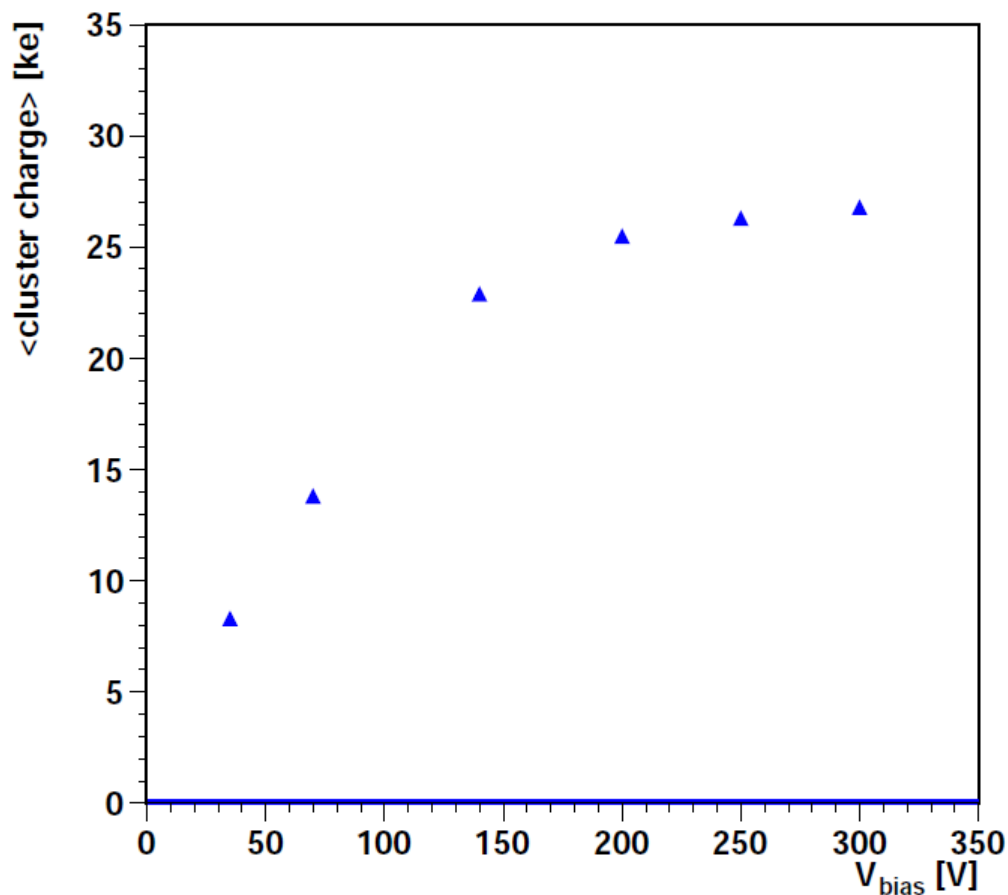
- ♦ psi46dig chip 202
 - > $D = 3$ Mrad
 - > $I_A = 25$ mA
 - > threshold = 35
 - > tilt = 20.3°
 - > turn = 28.5°

Cluster Size - Chip 203



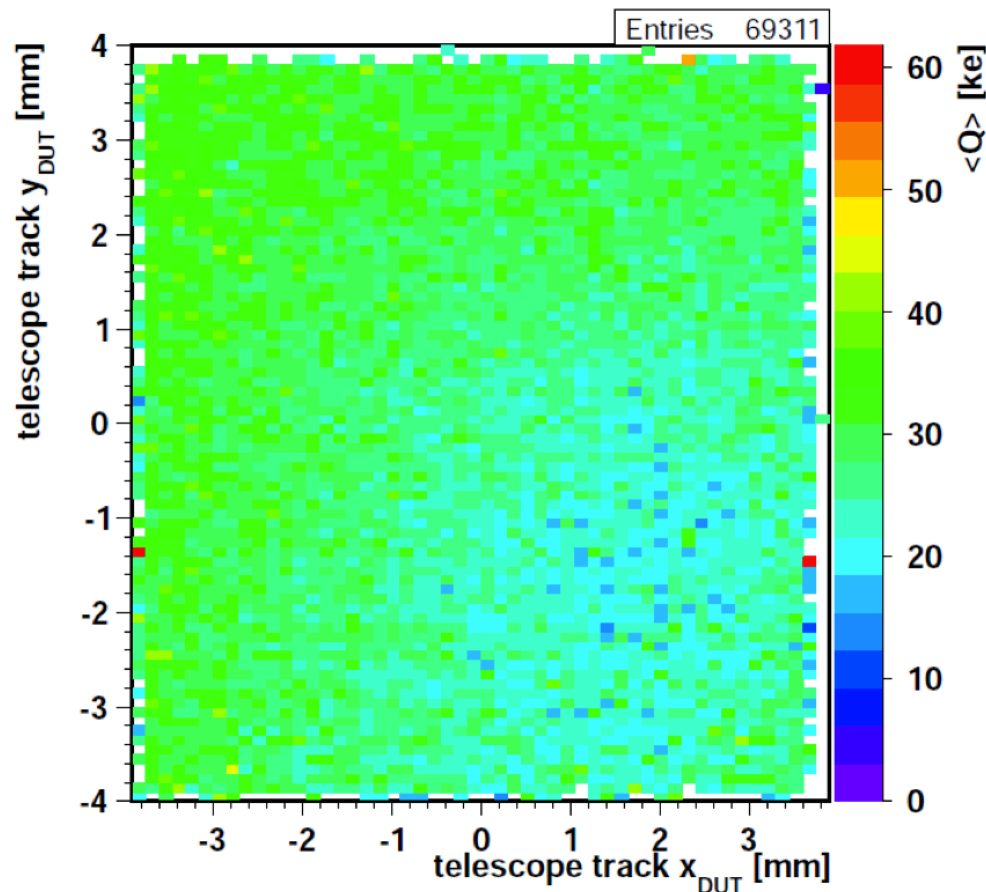
- ♦ psi46dig chip 203
 - > $D = 13$ Mrad
 - > $I_A = 25$ mA
 - > threshold = 35
 - > tilt = 22°
 - > no turn
 - > cooled
- ♦ Full depletion around -150 V

Cluster Charge - Chip 203



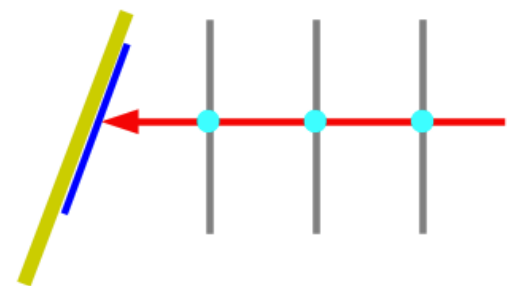
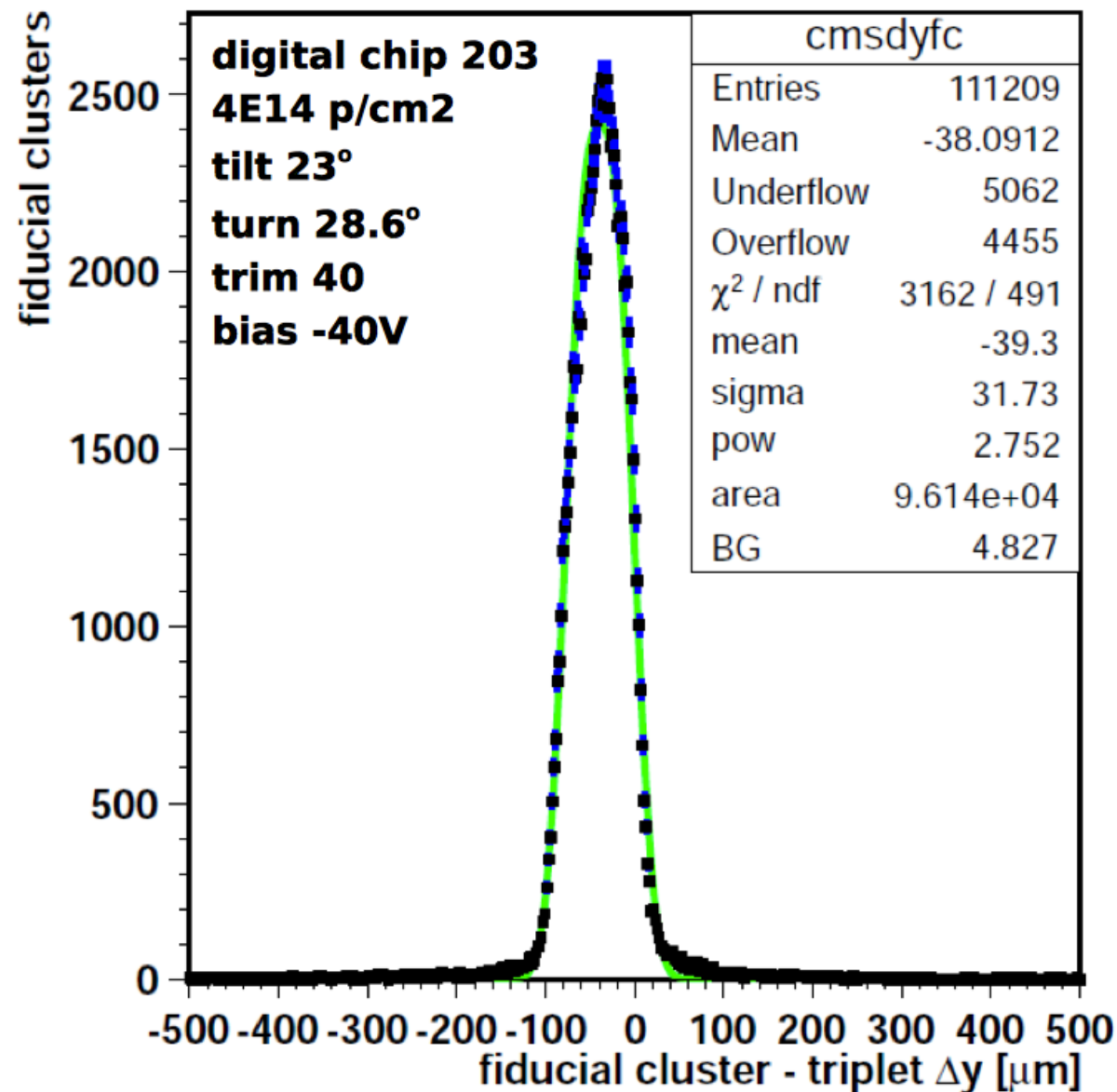
- ♦ psi46dig chip 203
 - > $D = 13 \text{ Mrad}$
 - > $I_A = 25 \text{ mA}$
 - > threshold = 35
 - > tilt = 22°
 - > no turn
 - > cooled
- ♦ Full depletion around -150 V ?

Charge Map - Chip 203



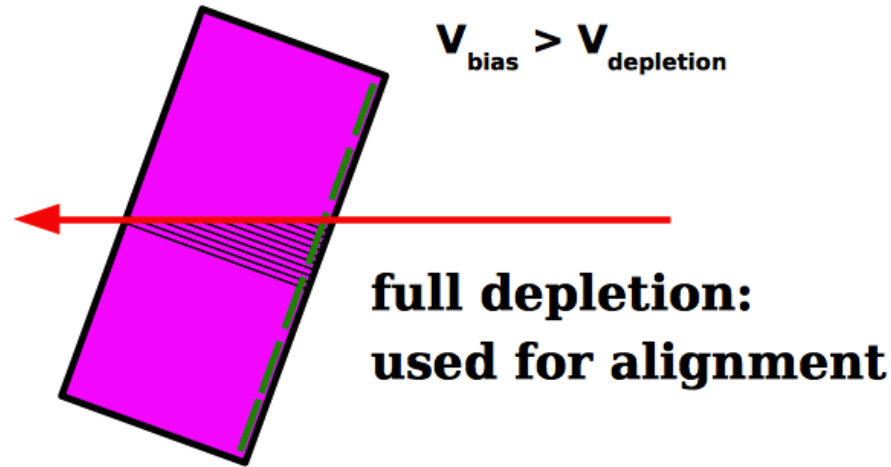
- ♦ psi46dig chip 203
 - > $D = 13$ Mrad
 - > $I_A = 25$ mA
 - > threshold = 35
 - > tilt = 23°
 - > turn = 29°
 - > cooled
- ♦ Valley in lower left quadrant

track-cluster residuals

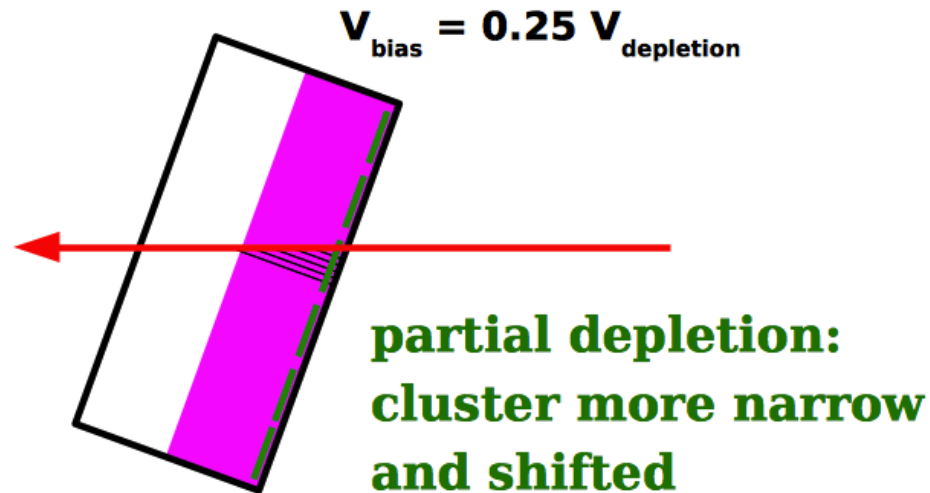


- digital chip 203:
 - 13 MRad
 - Ia 25 mA, trim 40
 - **bias -40V**
 - tilt 23°, turn 29°
- partial depletion and tilt:
 - **cluster shifted**

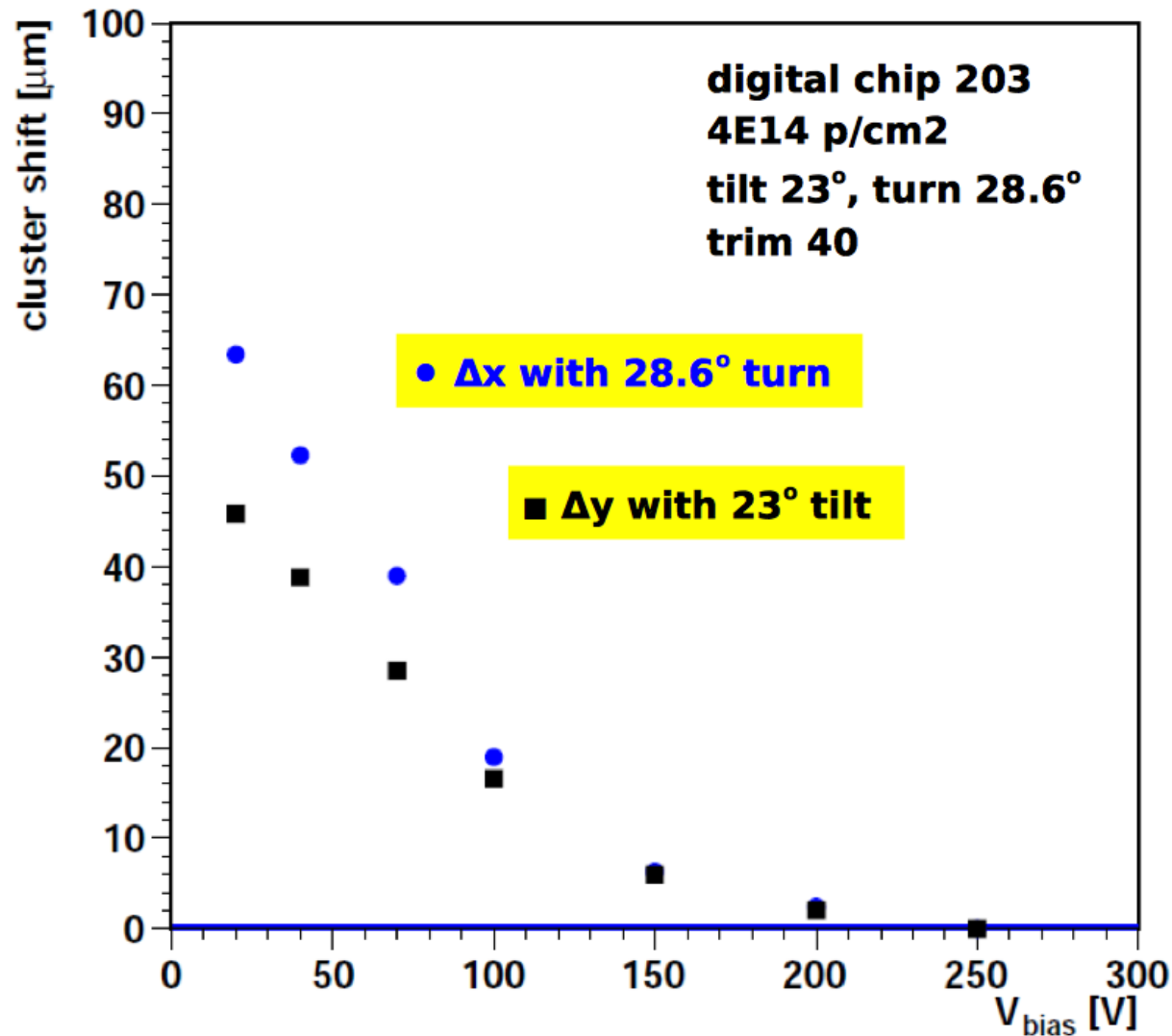
depletion depth



**irradiated:
type inversion,
depletion starts
from pixel side**

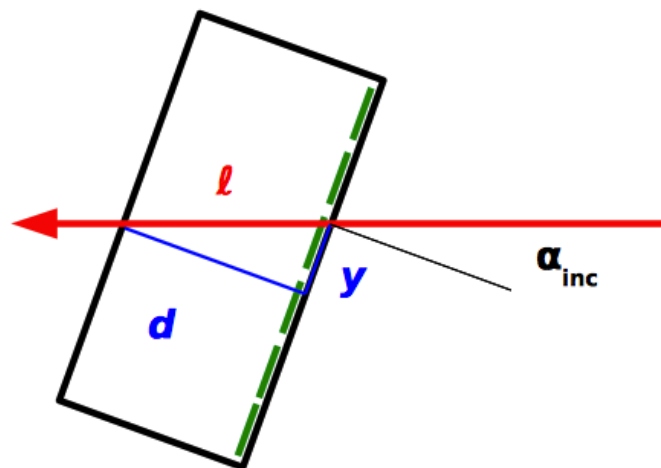


cluster shift vs bias voltage



- psi46dig chip 203:
 - 13 MRad
 - Ia 25 mA
 - trim 40
 - 23° tilt, turn 29°
- partial depletion
 - effective depth changes
- and tilt:
 - cluster position gets shifted

angles

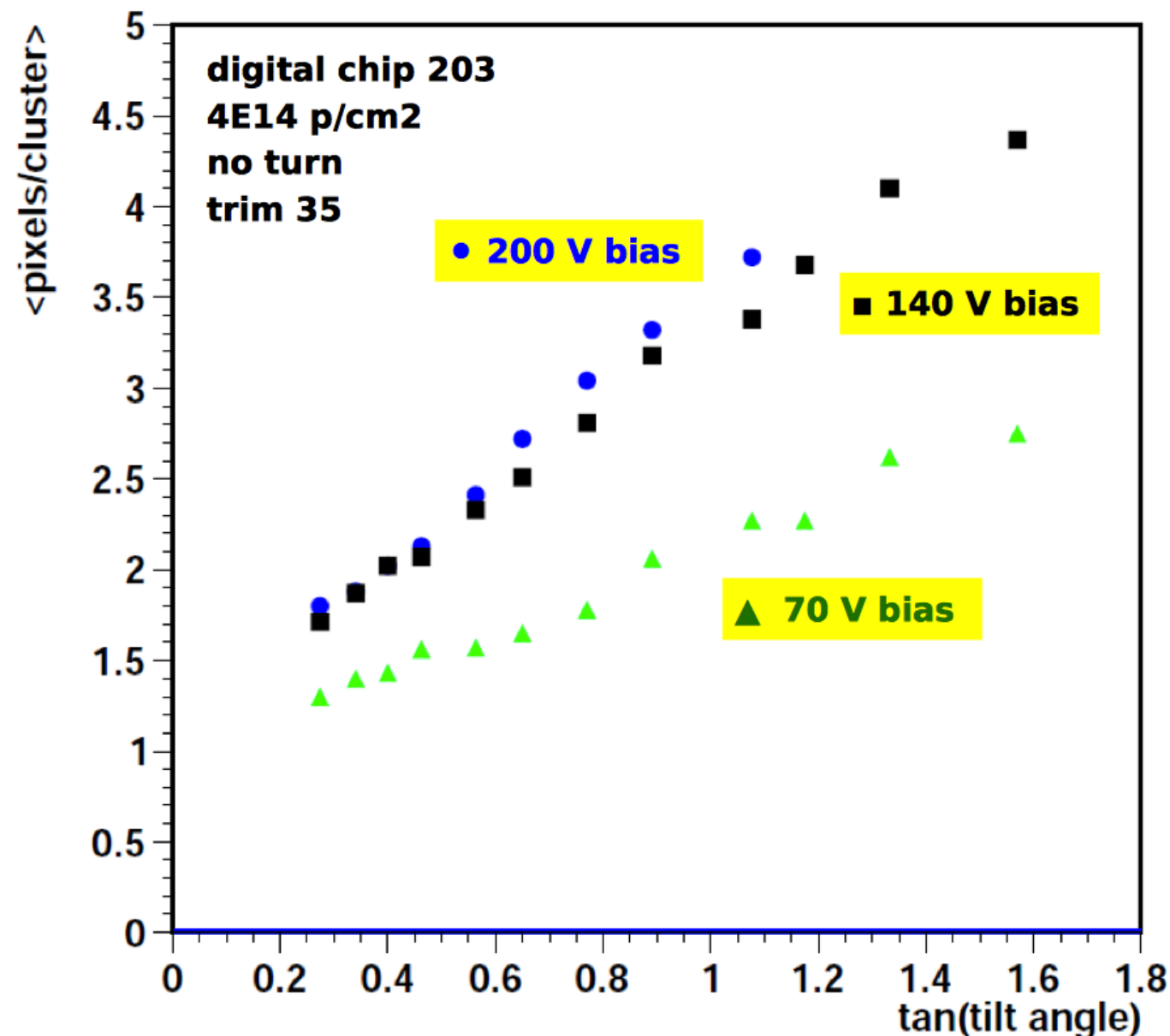


sensor thickness $d = 285 \mu\text{m}$

path length: $l = d / \cos\alpha$

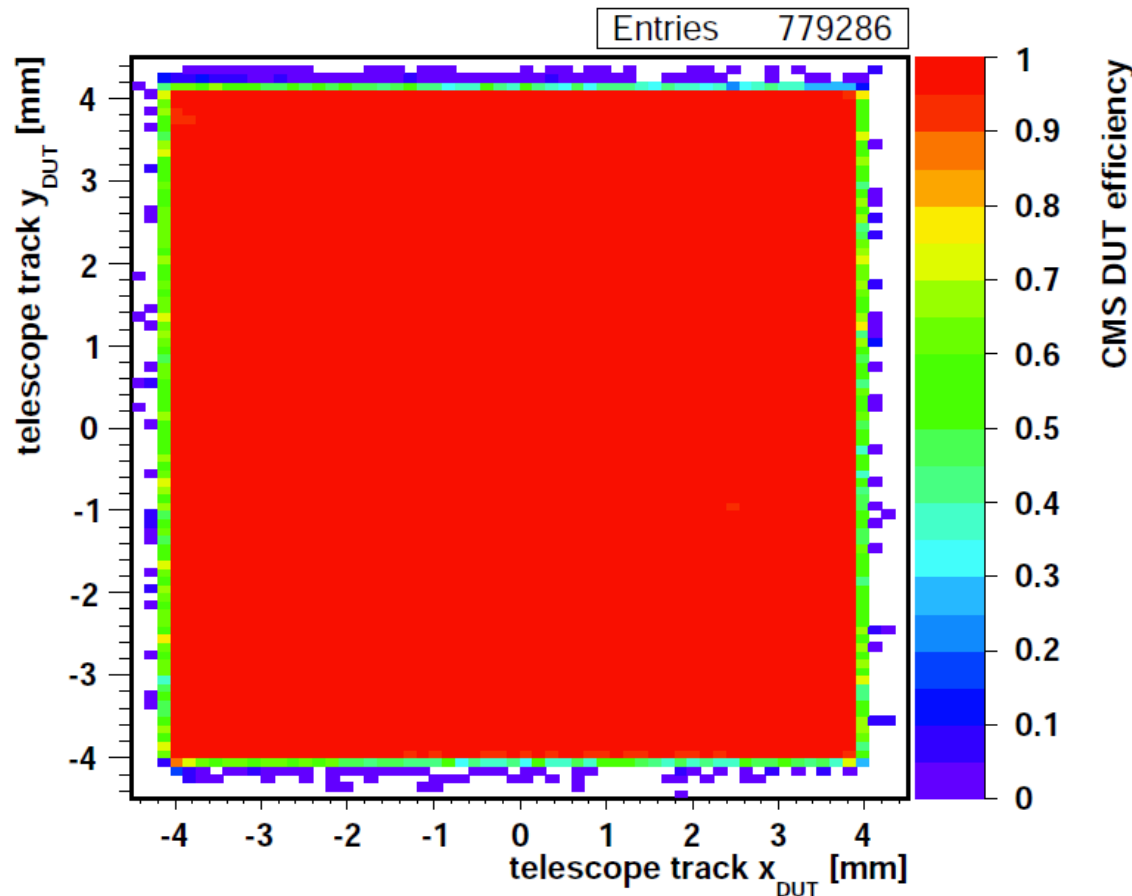
cluster width: $y = d \tan\alpha$

cluster size vs tilt angle and bias



- psi46dig chip 203:
 - 13 MRad
 - Ia 25 mA
 - trim 35
 - vary tilt, no turn
- cluster size scales with geometry:
 - $\sim \tan(\alpha_{\text{tilt}})$
- cluster size saturated at 140 V
 - full depletion

Efficiency Map - Chip 203



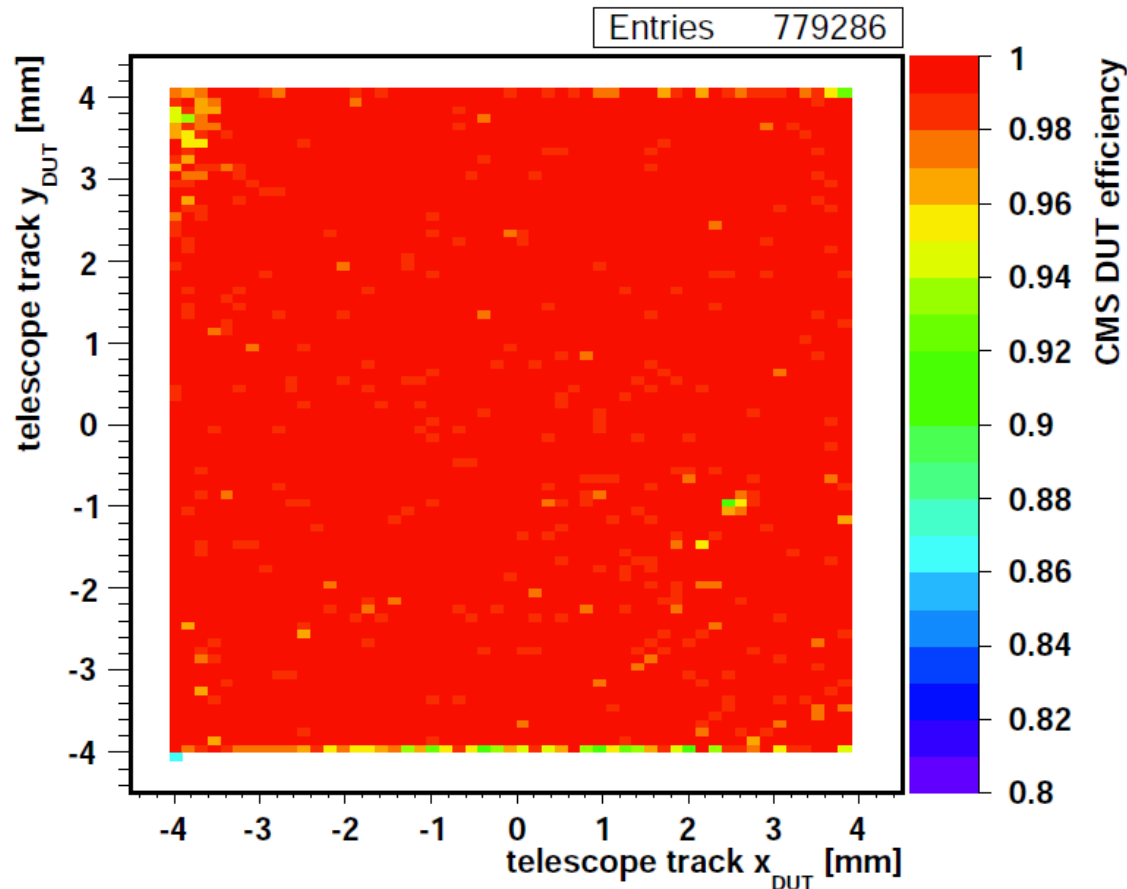
- ♦ psi46dig chip 203

- > D = 13 Mrad
- > I_A = 25 mA
- > threshold = 35
- > tilt = 22°
- > no turn
- > cooled

- ♦ 99.8 % in fiducial volume

Efficiency = (DUT linked cluster) / (telescope track with REF cluster)

Efficiency Map - Chip 203



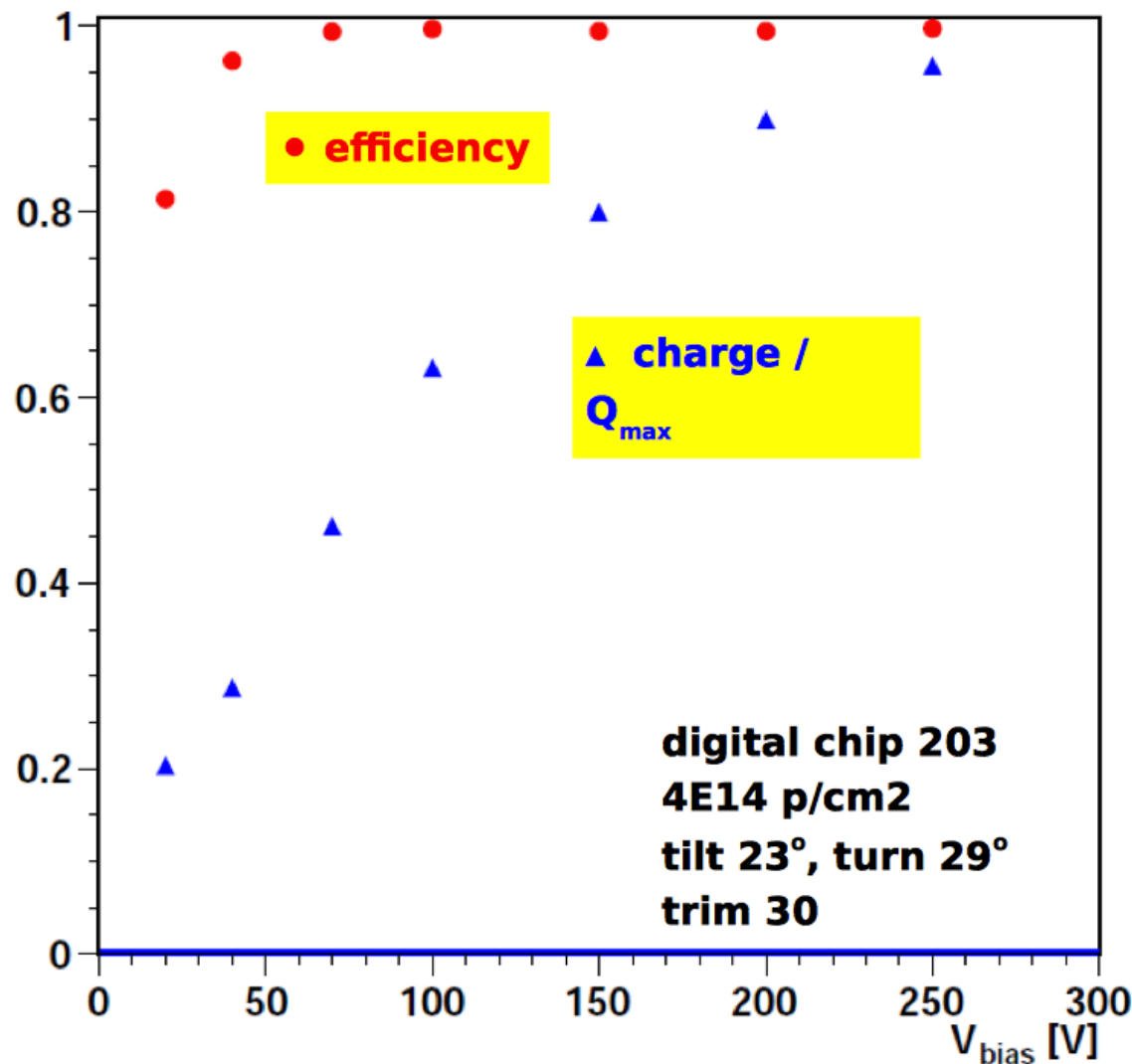
- ◆ psi46dig chip 203

- > $D = 13$ Mrad
- > $I_A = 25$ mA
- > threshold = 35
- > tilt = 22°
- > no turn
- > cooled

- ◆ 99.8 % in fiducial volume

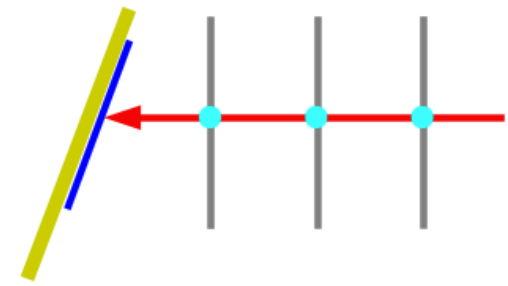
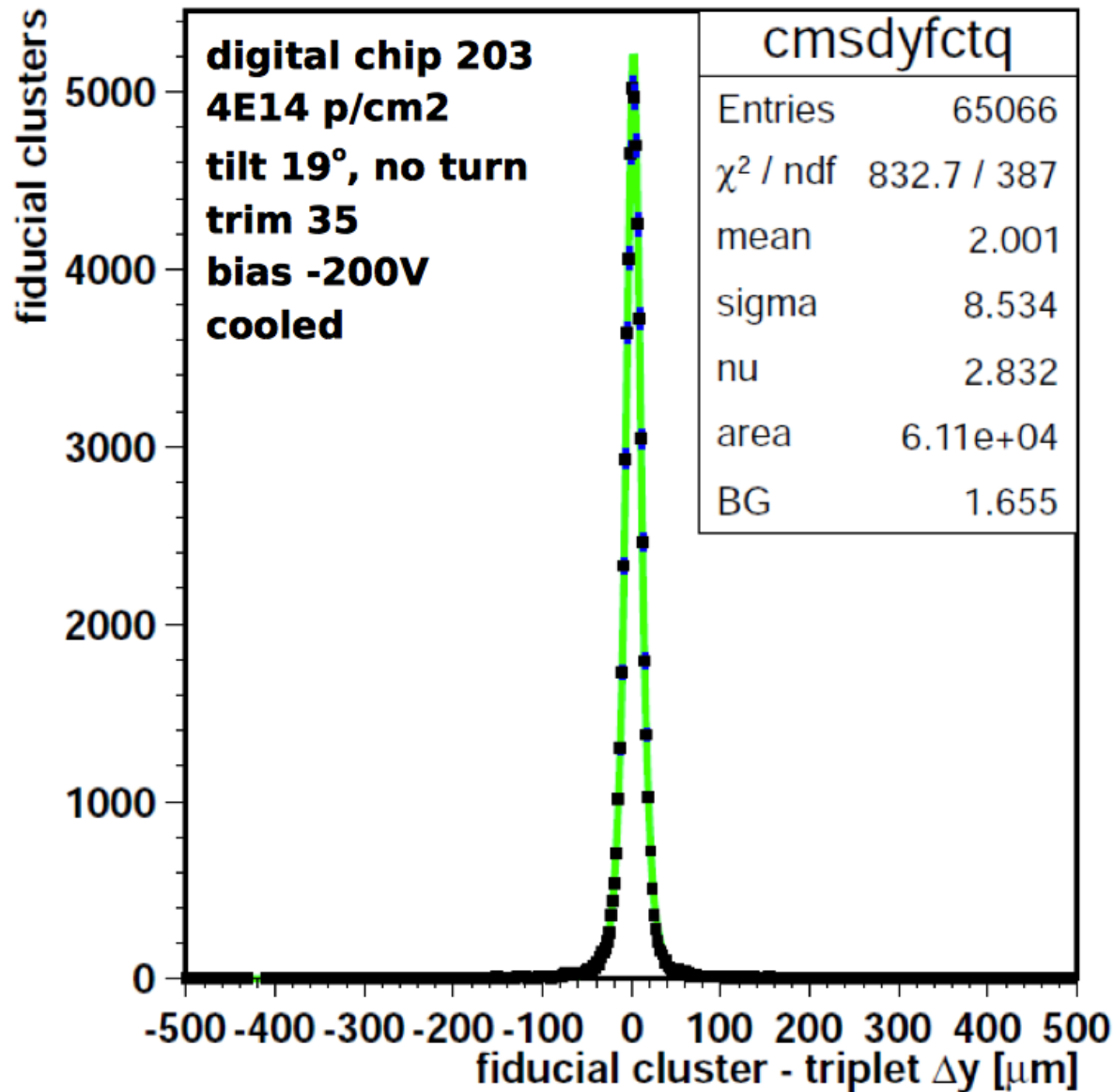
$$\text{Efficiency} = (\text{DUT linked cluster}) / (\text{telescope track with REF cluster})$$

efficiency vs bias voltage



- psi46dig chip 203:
 - 13 MRad
 - Ia 25 mA
 - trim 40
 - tilt 23°, turn 29°
- fully efficient down to 70 V bias
 - half the charge is enough!

resolution

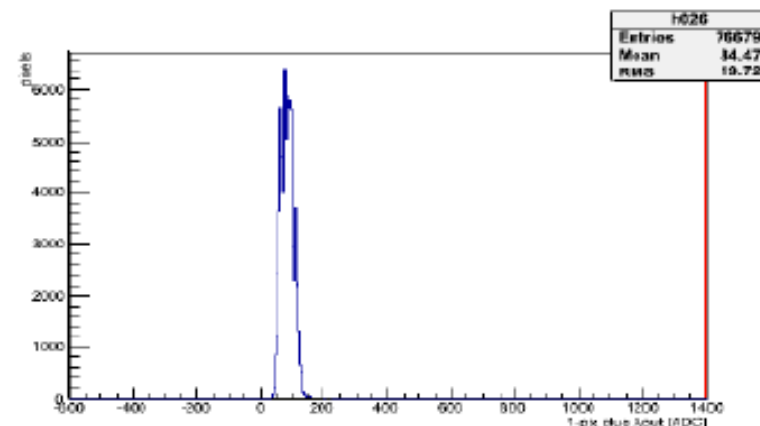
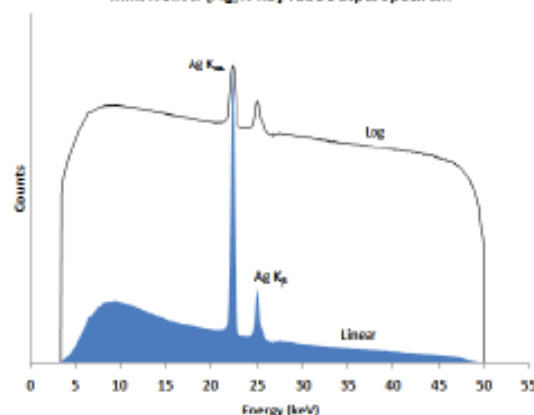


- digital chip 203:
 - 13 MRad
 - Ia 25 mA, trim 35
 - bias -200V, cooled
 - tilt 19°, no turn
- residual to track:
 - sigma 8.5 μm
 - subtract telescope resolution 4.6 μm
 - CMS pixel row resolution 7 μm
 - like before

x-ray Results

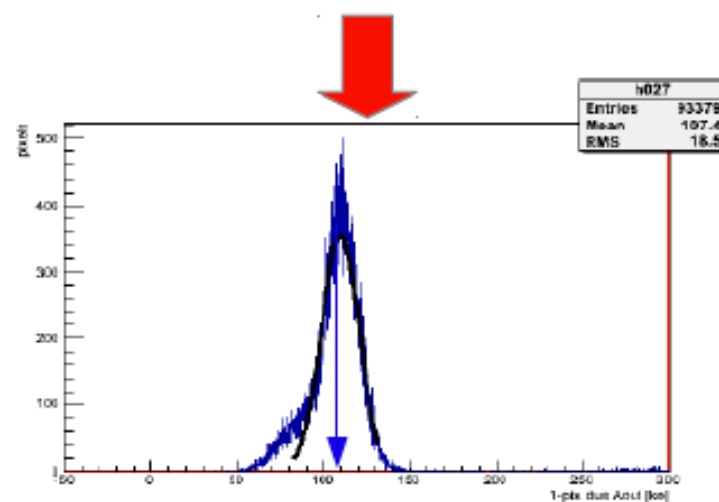
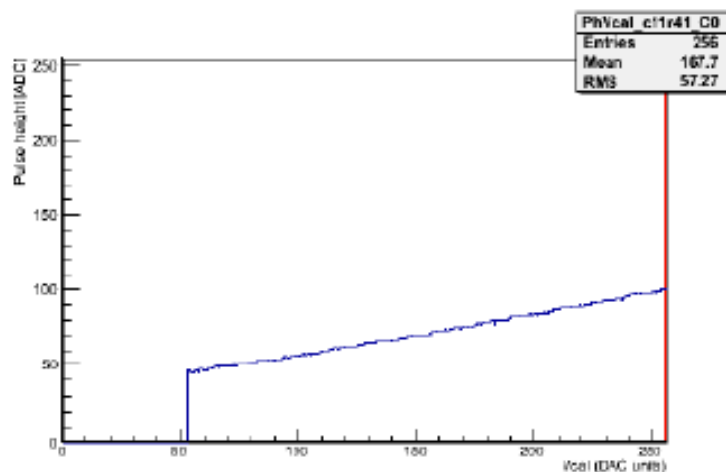
The Spectrum Method

Mini-X Silver (Ag) X-Ray Tube Output Spectrum



Choose specific energy with different targets

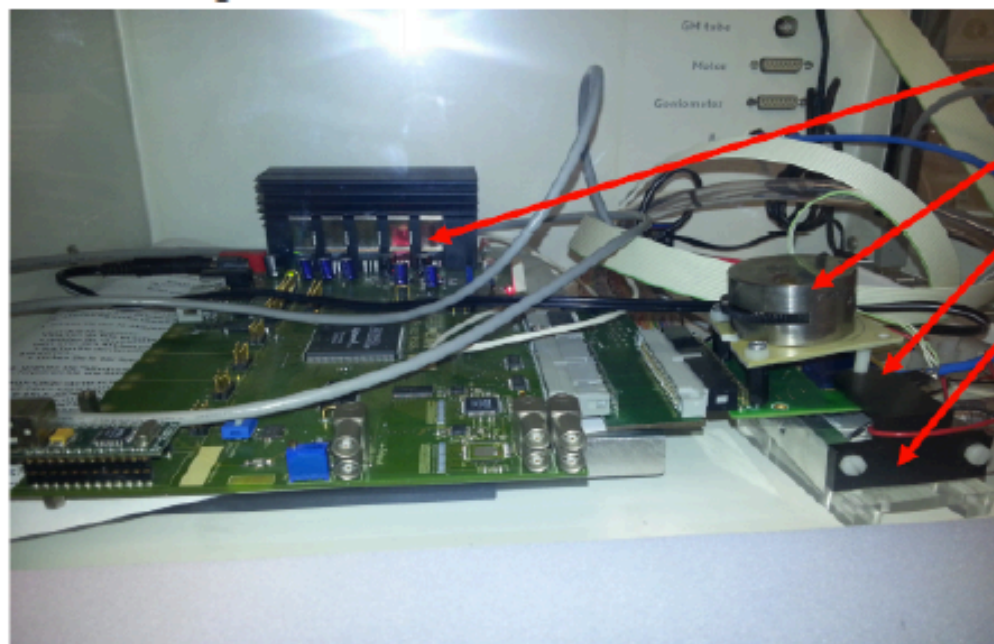
Measure ph-spectrum
in adc units



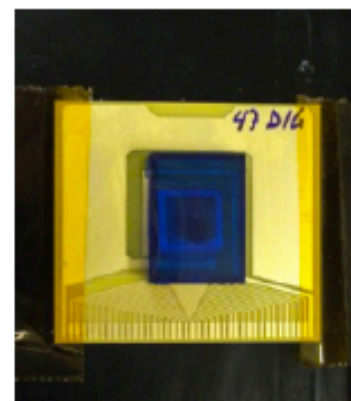
Do ph-calibration

Get ph-distribution in vcal units

Measurement Setup



- Testboard
- Variable X-ray source
- Digital single chip
- Cold block with peltiers



- Bias-voltage
= 200V

• 3 targets were used:

Mo: 17.48 keV (4.9 ke in Si)
 Ag: 22.16 keV (6.2 ke in Si)
 Ba: 32.19 keV (8.9 ke in Si)

Chip 202 (0.9×10^{14} p/cm²; 3Mrad)

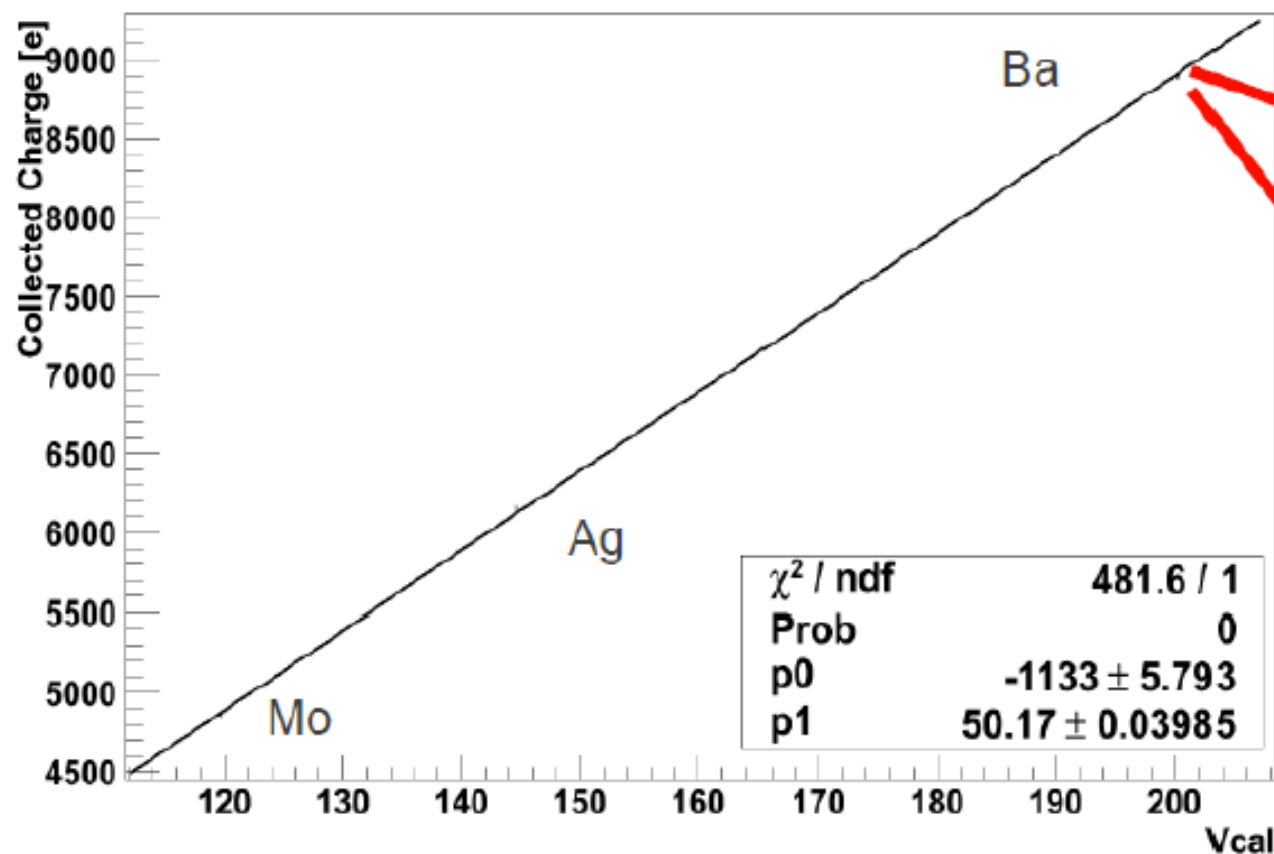
Calibrated at: -15° (Thr1= 35VCAL, Thr2= 50VCAL)
 +15° (Thr1= 35VCAL)

Chip 203 (4×10^{14} p/cm²; 13Mrad)

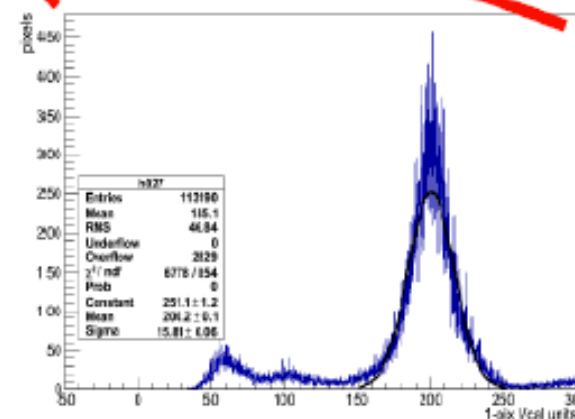
Calibrated at: -15° (Thr1= 35VCAL)

Chip 202: $T = -15^\circ$, $\text{Thr} = 35\text{Vcal}$

Chip202, -15C, Thr=35Vcal



- Calibration done with a threshold of 35Vcal
- Leakage current: 25uA



Lab Results

S-curves
time walk
gain

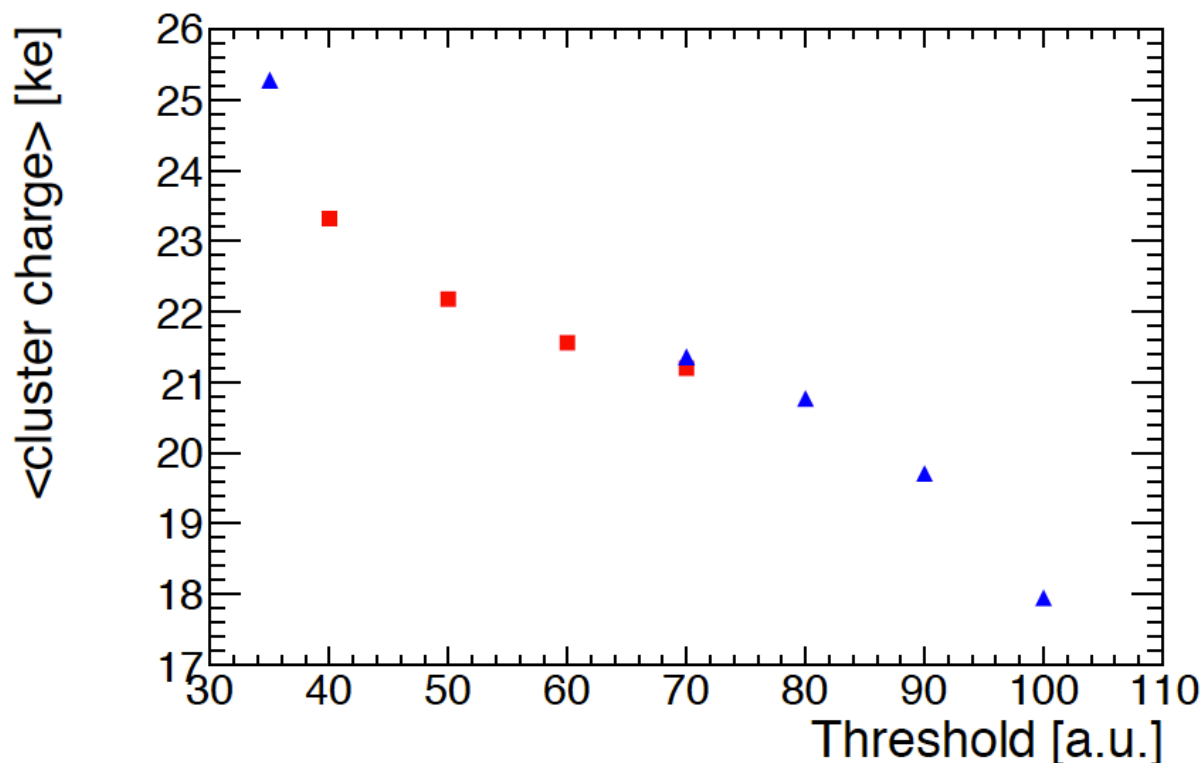
Summary & Outlook

- ❖ Test beam with irradiated digital ROCs done
- ❖ First analysis on data collected on April 2013
 - = depletion voltage about 150V
 - = similar resolution as un-irradiated $\sim 7 \mu\text{m}$
- ❖ Many features still to be investigated

Backup

Cluster Charge - Chip 202

Cluster charge vs Threshold



♦ psi46dig chip 202

> $D = 3$ Mrad

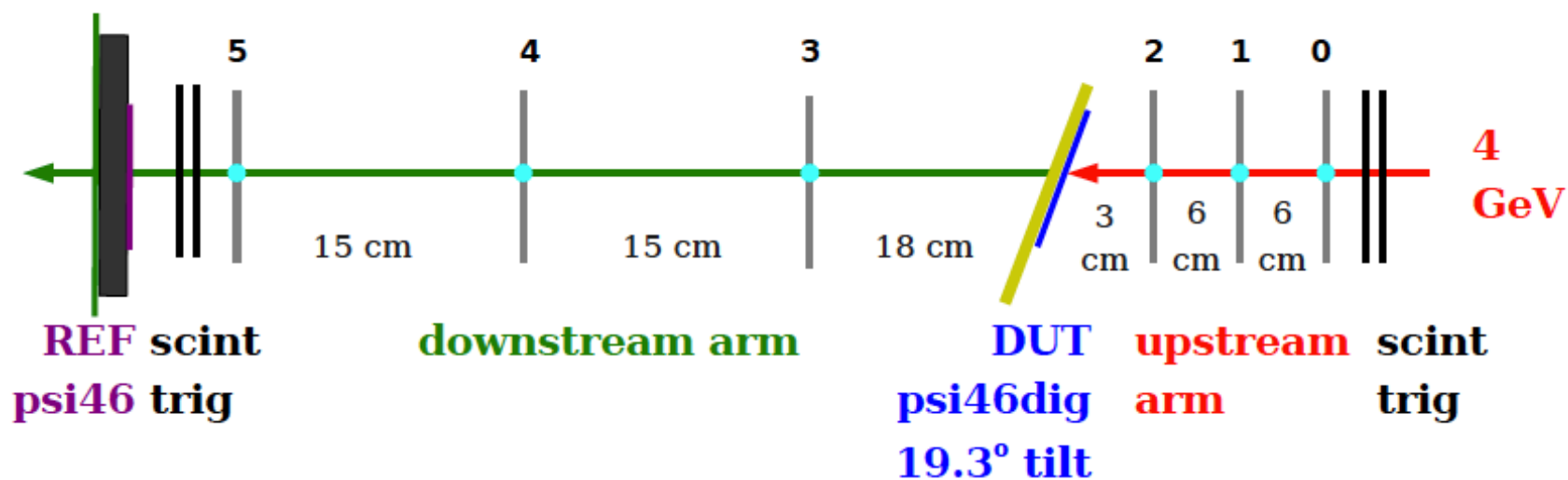
> $I_A = 25$ mA

> no turn

▲ $V_{bias} = -200$ V
 $tilt = 21^\circ$

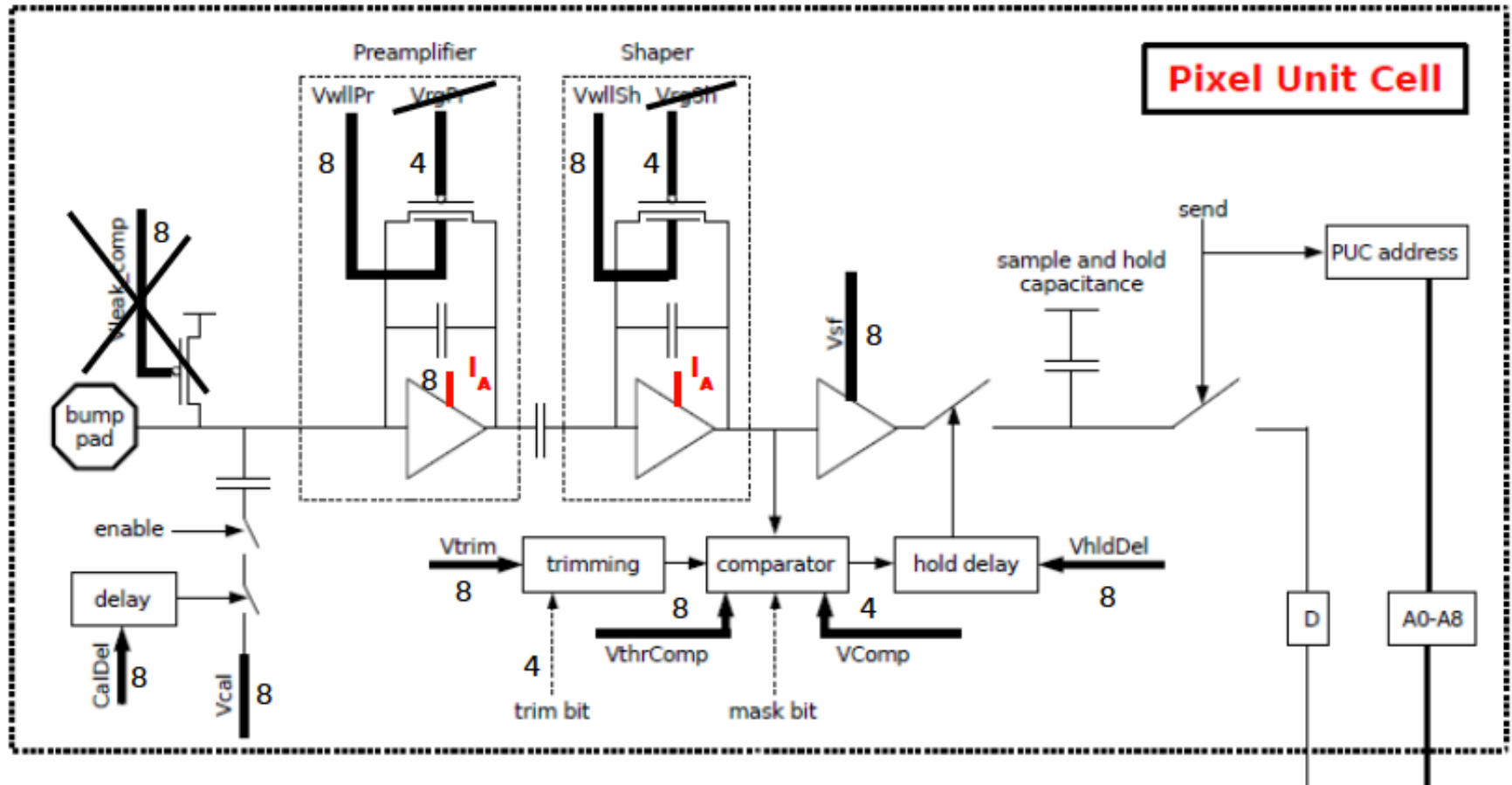
■ $V_{bias} = -150$ V
 $tilt = 17^\circ$

Test Beam Set Up



- Upstream arm 0-1-2:
 - as close as possible to DUT: 4.8 μm extrapolation error (at 4 GeV)
- DUT = single chip module, tilted by $19.3^\circ = \text{atan}(100 \mu\text{m} / 285 \mu\text{m})$
- Downstream arm 3-4-5:
 - equally spaced between DUT and REF
- REF = single chip module for timing, as close as possible behind scint
- trigger: 4-fold scintillator coincidence, $2 \times 1 \text{ cm}^2$ area

psi46dig Pixel Unit Cell



adjustable by programmable DAC

bits

supplied by analog current